L Number	Hits	Search Text	DB	Time stamp
1	1079	700/121.ccls.	USPAT;	2004/10/13 22:43
			US-PGPUB; EPO; JPO;	
2	218	700/121.ccls. and (delay or hysteresis)	IBM_TDB USPAT; US-PGPUB;	2004/10/13 22:51
3	210	700/121.ccls. and (delay or hysterisis)	EPO; JPO; IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2004/10/13 22:44
4	218	(700/121.ccls. and (delay or hysterisis)) or (700/121.ccls. and (delay or hysteresis)	IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2004/10/13 22:44
5	176	((700/121.ccls. and (delay or hysterisis)) or (700/121.ccls. and (delay or hysteresis))) and wafer	IBM_TDB USPAT; US-PGPUB; EPO; JPO; IBM TDB	2004/10/13 22:57
6	111	(((700/121.ccls. and (delay or hysterisis)) or (700/121.ccls. and (delay or hysteresis))) and wafer) and (model\$5 or simulat\$5 or	USPAT; US-PGPUB; EPO; JPO;	2004/10/13 22:57
7	27	emulat\$5) ((((700/121.ccls. and (delay or hysterisis)) or (700/121.ccls. and (delay or hysteresis))) and wafer) and (model\$5 or simulat\$5 or emulat\$5)) and (voltage and current)	IBM_TDB USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:52
8	4	((((700/121.ccls. and (delay or hysterisis)) or (700/121.ccls. and (delay or hysteresis))) and wafer) and (model\$5 or simulat\$5 or emulat\$5)) and (threshold with	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:57
9	95	voltage) 700/108.ccls. and (delay or hysteresis)	USPAT; US-PGPUB; EPO; JPO;	2004/10/13 22:57
10	93	700/108.ccls. and (delay or hysterisis)	IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2004/10/13 22:52
11	95	(700/108.ccls. and (delay or hysteresis)) or (700/108.ccls. and (delay or hysterisis)	IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2004/10/13 22:52
12	34	((700/108.ccls. and (delay or hysteresis)) or (700/108.ccls. and (delay or hysterisis))) and wafer	IBM_TDB USPAT; US-PGPUB; EPO; JPO;	2004/10/13 22:52
13	24	(((700/108.ccls. and (delay or hysteresis)) or (700/108.ccls. and (delay or hysterisis))) and wafer) and (model\$5 or simulat\$5 or emulat\$5)	IBM_TDB USPAT; US-PGPUB; EPO; JPO; IBM TDB	2004/10/13 22:52
14	7	I	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:52
15	2	current)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/10/13 22:52
16	50	,	USPAT; US-PGPUB; EPO; JPO; IBM TDB	2004/10/13 22:58

18					
18	17	18	(700/109.ccls. and (delay or hysterisis or hysteresis)) and wafer		2004/10/13 22:58
18			hysteresis, / and warer		
hysteresis) and wafer) and (model\$5 or simulat\$5 or emulat\$5 o				IBM_TDB	
SimulatS5 or emulatS5 Series Seri	18	. 13	((700/109.ccls. and (delay or hysterisis or	· •	2004/10/13 22:58
18					
19			simulat\$5 or emulat\$5)		
	19	0	(((700/109.ccls. and (delay or hysterisis or		2004/10/13 22:58
Simulat\$5 or emulat\$5) and (threshold with EPO, JPO; 100, 101, 102, 102, 103, 103, 103, 103, 103, 103, 103, 103			hysteresis)) and wafer) and (model\$5 or		2000, 20, 20
2004/10/13 22:58			simulat\$5 or emulat\$5)) and (threshold with		
hysteresis			voltage)		
19	20	50		1	2004/10/13 22:58
19			Mysteresis/		
22					
1	21	19	(700/110.ccls. and (delay or hysterisis or		2004/10/13 22:58
1			hysteresis)) and wafer		
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hysteresis) and wafer) and (model\$5 or simulat\$5 or emulat\$5)	22	111	//700/110 ccls and (delay or hysterisis or	-	2004/10/13 22:58
Simulat\$5 or emulat\$5	22	1		,	2004/10/13 22.30
2					
hysteresis and wafer) and (model\$s or simulat\$s) and (threshold with voltage) 12 ((BERTSCH-JOHN-E BERTSCH-JOHN-EDWARD BERTSCH-JOHN COOPS-DANIEL-S FRIED-DAVID PRIED-DAVID) 10					
Simulat\$5 or emulat\$5) and (threshold with voltage)	23	2			2004/10/13 22:58
Voltage (IGBETSCH-JOHN-E BERTSCH-JOHN-EDWARD BERTSCH-JOHN COOPS-DANIEL-S FRIED-DAVID IBM TDB USPAT; BERTSCH-JOHN-EDWARD USPAT; BERTSCH-JOHN COOPS-DANIEL-S FRIED-DAVID US-PGPUB; FRIED-DAVID-M).in. BERTSCH-JOHN-EDWARD USPAT; BERTSCH-JOHN COOPS-DANIEL-S FRIED-DAVID US-PGPUB; EPO; JPO; IBM TDB USPAT; BERTSCH-JOHN COOPS-DANIEL-S FRIED-DAVID US-PGPUB; EPO; JPO; IBM TDB USPAT; US-PGPUB; EPO; JPO; JPO; IBM TDB USPAT; US-PGPUB; EPO; JPO; JPO; JPO; JPO; JPO; JPO; JPO; J					
2					
FRIED-DAVID-M.in.) and (simulat\$5 or emulat\$5) - 43 43 43 43 43 ERRISCH-JOHN-E BERTSCH-JOHN-EDWARD BERTSCH-JOHN-E DERTSCH-JOHN-EDWARD FRIED-DAVID FRIED-DAVID FRIED-DAVID-M.in. - 1 (model same hardware same correlation) and MHC - 140 model same hardware same correlation - 140 model same hardware same correlation - 11 model with hardware with correlation - 11 model near3 hardware near3 correlation - 11 model near3 hardware near3 correlation - 223 (wafer with final with test - 223 (wafer with final with test) and (line with test) - 1 (wafer with final with test) and (in with line with test) - 1 (model same hardware same correlation) and (wafer with final with test) and (in with line with test) - 1 (model same hardware same correlation) and (wafer with final with test) and (in with line with test) - 1 (model same hardware same correlation) and (wafer with final with test) and (in with line with test) - 1 (model same hardware same correlation) and (wafer with final with test) and (in with line with test) - 1 (model same hardware same correlation) and (wafer with final with test) and (in with line with test) - 1 (model same hardware same correlation) and (wafer with final with test) and (in with line with test) - 1 (model same hardware same correlation) and (wafer with final with test) and (in with line with test) - 2004/10/01 10:57 2004/10/01 10:57	_	- 2		_	2004/10/01 10:29
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A3 (BERTSCH-JOHN - BERTSCH-JOHN - EDWARD BERTSCH-JOHN COOPS-DANIEL-S FRIED-DAVID US-PGPUB; EPO; JPO; IBM TDB USPAT; US-PGPUB; EPO; JPO; JPO; IBM TDB USPAT; US-PGPUB; EPO; JPO; IBM TDB			l · · · · · · · · · · · · · · · · · · ·	I	
BERTSCH-JOHN COOPS-DANIEL-S FRIED-DAVID US-POPUB; EPO; JPO; IBM TDB USPAT; US-POPUB; EPO; JPO;		42	1	_	2004/00/20 12:00
FRIED-DAVID-M).in. (model same hardware same correlation) and WFAT; US-PGPUB; EFP; JPO; IBM_TDB USPAT; US-PGPUB; EFO; JP	-	4.3			2004/09/30 12:06
1			!		
MHC				_	
140 model same hardware same correlation	-	1	1		2004/10/01 10:29
140 model same hardware same correlation IBM_TDB USPAT; US-PGPUB; EPO; JPO; IBM_TDB USPAT; US-PGPUB; EPO; JPO; ISM_TDB USPAT; US-PGPUB; EPO;			MHC	1	
140 model same hardware same correlation					
model with hardware with correlation The model with hardware with correlation The model near3 hardware near3	_	140	model same hardware same correlation		2004/10/01 10:30
TIM_TDB USPAT; US-PGPUB; EPO; JPO; IBM_TDB USPAT; U					
21 model with hardware with correlation					-
US-PGPUB; EPO; JPO; IBM_TDB USPAT;	_	21	model with hardware with correlation		2004/10/01 10:38
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model near3 hardware near3 correlation USPAT; US-PGPUB; EPO; JPO; IBM_TDB					
Wafer with final with test - 223 (wafer with final with test) and (line with test) - 223 (wafer with final with test) and (line with test) - 91 (wafer with final with test) and (in with line with test) - 1 (model same hardware same correlation) and ((wafer with final with test) and (in with line with test)) - 1 (model same hardware same correlation) and ((wafer with final with test) and (in with line with test)) - 1581 (mos or cmos or mosfet) same (verify or verification or verifying) - 1581 (mos or cmos or mosfet) same (verify or verification or verifying) - 1581 (mos or cmos or mosfet) same (verify or verification or verifying) - 1581 (mos or cmos or mosfet) same (verify or verification or verifying)				_	
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EPO; JPO;		1301	verification or verifying)		ZUU4/10/U1 11:23
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-	248	((mos or cmos or mosfet) same (verify or	USPAT; US-PGPUB;	2004/10/01 11:24
		verification or verifying)) and wafer	EPO; JPO;	
			IBM TDB	
	8	(((mos or cmos or mosfet) same (verify or	USPAT;	2004/10/01 11:40
		verification or verifying)) and wafer) and	US-PGPUB;	2000, 20, 02 22.10
		(source adj current) and (drain adj current)	EPO; JPO;	
		(bourse daj sarrene, and (aran)	IBM TDB	
_	89	(((mos or cmos or mosfet) same (verify or	USPAT;	2004/10/01 11:26
		verification or verifying)) and wafer) and	US-PGPUB;	
		(source with current) and (drain with	EPO; JPO;	
		current)	IBM_TDB	
-	3	((((mos or cmos or mosfet) same (verify or	USPAT;	2004/10/01 11:27
*		verification or verifying)) and wafer) and	US-PGPUB;	
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		current)) and (AC or (alternating adj	IBM_TDB	
		current))	**************************************	2004/10/01 11 05
-	3		USPAT;	2004/10/01 11:27
		verification or verifying)) and wafer) and (source with current) and (drain with	US-PGPUB; EPO; JPO;	
		current)) and (AC or (alternating adj	IBM TDB	
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_	15		USPAT;	2004/10/01 17:00
		verification or verifying)) and wafer) and	US-PGPUB;	2001, 10, 01 17.00
		(spice)	EPO; JPO;	
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_	93	(spice and wafer and model and (test or	USPAT;	2004/10/01 17:01
		verif\$7) and parameter) and @ad<20010529	US-PGPUB;	
			EPO; JPO;	
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-	151	spice and wafer and model and (test or	USPAT;	2004/10/12 13:44
		verif\$7) and parameter	US-PGPUB;	
			EPO; JPO;	
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_	5	spice and wafer and model and (test or	USPAT;	2004/10/06 17:07
		verif\$7) and parameter and 702/\$3.ccls.	US-PGPUB; EPO; JPO;	
ļ.			IBM TDB	
_	185	spice and (wafer and model) and (test or	USPAT;	2004/10/12 13:45
		verif\$7)	US-PGPUB;	
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-	39	spice and ((wafer and model) same (test or	USPAT;	2004/10/12 13:45
		verif\$7))	US-PGPUB;	
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		verif\$7) and kerf	US-PGPUB;	٠
		1 ,	EPO; JPO;	
	23	korf game oggillator	IBM_TDB	2004/10/12 22:42
_	23	kerf same oscillator	USPAT;	2004/10/13 22:43
			US-PGPUB; EPO; JPO;	
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